IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): OOHARA et al.

Atty. Dkt.: 01-542

Serial No.: Unknown

Group Art Unit:

Filed: Concurrently herewith

Examiner:

Title: OPTICAL DEVICE HAVING

MICRO LENS ARRAY AND

METHOD FOR MANUFACTURING

THE SAME

Date: January 20, 2004

Commissioner for Patents Arlington, VA 22202

Sir:

Pursuant to 37 C.F.R. §1.56, the reference(s) listed on the attached Form PTO-1449 is/are submitted for consideration by the Examiner without any admission that it/they constitute(s) statutory prior art, or without any admission that it/they contain(s) subject matter that anticipates the invention or renders the invention obvious to a person of ordinary skill in the art.

INFORMATION DISCLOSURE STATEMENT

The Examiner is requested to initial the attached PTO Form-1449 and to return a copy of same to the undersigned attorney as proof that the listed reference(s) has/have been considered and made of record.

Respectfully submitted,

David G. Posz Reg. No. 37,701

Posz & Bethards, PLC 11250 Roger Bacon Drive, Suite 10 Reston, VA 20190 (703)707-9110 (phone) Customer No. 23400

* PATENT APPLICATION

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	APPLICANT	OOHARA et al.	
	FILING DATE	January 20, 2004	GROUP

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	 DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

TRANSLATION

						IKANSLATION	
DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
JP-A-H06-194502* (Discussed in page 1 of the spec.)	07/15/94	JAPAN				X (Abstract)	
JP-A-2002-231945* (Discussed in page 12 of the spec.)	8/16/02	JAPAN		; -		X (Abstract)	
JP-A-2000-299310* (Discussed in page 17 of the spec.)	10/24/00	JAPAN				X (Abstract)	
JP-A-H09-90104*	4/4/97	JAPAN				X (Abstract)	
JP-A-2003-7987*	1/10/03	JAPAN				X (Abstract)	
JP-A-H05-218494*	8/27/93	JAPAN				X (Abstract)	
	JP-A-H06-194502* (Discussed in page 1 of the spec.) JP-A-2002-231945* (Discussed in page 12 of the spec.) JP-A-2000-299310* (Discussed in page 17 of the spec.) JP-A-H09-90104* JP-A-2003-7987*	JP-A-H06-194502* (Discussed in page 1 of the spec.) JP-A-2002-231945* (Discussed in page 12 of the spec.) JP-A-2000-299310* (Discussed in page 17 of the spec.) JP-A-H09-90104* JP-A-2003-7987* 1/10/03	JP-A-H06-194502* (Discussed in page 1 of the spec.) JP-A-2002-231945* (Discussed in page 12 of the spec.) JP-A-2000-299310* (Discussed in page 17 of the spec.) JP-A-H09-90104* JP-A-2003-7987* 1/10/03 JAPAN	JP-A-H06-194502* (Discussed in page 1 of the spec.) JP-A-2002-231945* (Discussed in page 12 of the spec.) JP-A-2000-299310* (Discussed in page 17 of the spec.) JP-A-H09-90104* JP-A-2003-7987* 1/10/03 JAPAN	JP-A-H06-194502* (Discussed in page 1 of the spec.) JP-A-2002-231945* (Discussed in page 12 of the spec.) JP-A-2000-299310* (Discussed in page 17 of the spec.) JP-A-H09-90104* JP-A-2003-7987* 1/10/03 JAPAN	JP-A-H06-194502* (Discussed in page 1 of the spec.) JP-A-2002-231945* (Discussed in page 12 of the spec.) JP-A-2000-299310* (Discussed in page 17 of the spec.) JP-A-H09-90104* JAPAN JAPAN JAPAN JAPAN JP-A-2003-7987* 1/10/03 JAPAN JAPAN	DOCUMENT NUMBER DATE COUNTRY NAME CLASS SUB CLASS YES

^{*} Full English text is available in machine-translated form in JPO (Japanese Patent Office) English language web site at http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX.

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

		1.
EXAMINER		DATE CONSIDERED

Rev. 10/94 (Form 3.05)